AMENDMENTS TO THE CLAIMS

1. (Currently Amended) In an electronic device, a method, comprising the steps of:

providing simulation output from a simulation of an electrical component, said simulation output containing information regarding a data signal and a clock signal;

providing an automated tool for analyzing the information in the simulation output regarding the data signal and the clock signal and for producing a report of results of the analysis;

receiving user-specified parameters at the tool; ~~and~~

applying the user-specified parameters to configure the analysis performed by the tool; and

performing the analysis of the simulation output with the tool to produce the report of the analysis.

2. (Original) The method of claim 1 further comprising the step of performing error checking on the simulation output to identify any errors in the simulation output.

3. (Original) The method of claim 1, wherein the report contains information regarding hold times of the data signal.

4. (Original) The method of claim 1, wherein the report contains information regarding setup times of the data signal.

5. (Original) The method of claim 1, wherein the report contains information regarding data jitter.

6. (Original) The method of claim 1, wherein the simulation output contains information regarding the data signal and the clock signal for a simulated time period and wherein the user-specified parameters include a specification of a portion of the simulated time period to which the analysis is to be applied.

7. (Original) The method of claim 1, wherein the user-specified parameters include a specification of a voltage reference window extending from a logically high reference voltage to a logically low reference voltage.

8. (Original) The method of claim 1, wherein the data signal is single-ended.

9. (Original) The method of claim 1, wherein the data signal is differential.

10. (Currently Amended) A storage medium for use with an electronic device, said medium holding instructions executable by the electronic device for performing a method, said method comprising the steps of:

receiving user-specified parameters regarding an analysis of a simulation output from a simulation of an electrical component, said simulation output containing information regarding a data signal and a clock signal;

applying the user-specified parameters to configure the analysis; and

performing the analysis of the simulation output to produce a report of the analysis.

11. (Original) The storage medium of claim 10, wherein the method further comprises the step of performing error checking on the simulation output to identify errors in the simulation output.

12. (Original) The storage medium of claim 10, wherein the report contains information regarding hold times of the data signal.

13. (Original) The storage medium of claim 10, wherein the report contains information regarding setup times of the data signal.

14. (Original) The storage medium of claim 10, wherein the report contains information regarding data jitter.

15. (Original) The storage medium of claim 10, wherein the simulation output contains information regarding the data signal and the clock signal for a simulated time period and wherein the user-specified parameters include a specification of a portion of the simulated time period to which the analysis is to be applied.

16. (Original) The storage medium of claim 10, wherein the user-specified parameters include a specification of a voltage reference window extending from a logically high reference voltage to a logically low reference voltage.

17. (Original) The storage medium of claim 10, wherein the data signal is single-ended.

18. (Original) The storage medium of claim 10, wherein the data signal is differential.

19. (Original) In an electronic device, a method, comprising the steps of:

providing results of simulation of an electrical component wherein said results contain waveform representations of a data signal and a clock signal over a simulated time period; and

with an automated analysis facility, processing the results of the simulation to identify data jitter for the data signal.

20. (Original) The method of claim 19, wherein the method further comprises the step of producing a report containing information regarding the data jitter for the data signal.

21. (Original) The method of claim 19, wherein the step of processing the results processes the results for only a portion of the simulated time period.

22. (Original) A storage medium holding instructions of an automated analysis facility that are executable by an electronic device for performing a method, said method comprising the steps of:

providing results of simulation of an electrical component wherein said results contain waveform representations of a data signal and a clock signal over a simulated time period; and

with an automated analysis facility, processing the results of the simulation to identify data jitter for the data signal.